PATENT

Docket No.: 29284/541

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

LICANTS:

SERIAL NO.:

**FILED** 

**FOR** 

ARA, Yasuhiko et al.

9/832,220

April 11, 2001

INSPECTION METHOD, APPARATUS AND SYSTEM FOR CIRCUIT PATTERN

**ART UNIT** 

EXAMINER:

ASSISTANT COMMISSIONER

FOR PATENTS

Washington, DC 20231

## **AMENDMENT**

SIR:

In response to the Office Action of August 24, 2001, the period for response having been extended herein to February 25, 2002 (February 24th falls on a Sunday) by payment of the requisite fee of \$920.00 for a Petition for Extension of Time Under 37 C.F.R. § 1.136(a), kindly amend the aboveidentified application as follows:

## **IN THE CLAIMS:**

Cancel claims 6-8 without prejudice. Amend the following claims:

1. (Amended) An inspection apparatus for a circuit pattern, comprising:

09832220

2002 NHOHAHH1 00000074 110600

01 FC:117

320.00 CH